

**Notice of Reference Cited**

Application/Control No.

10/02 ,566

Applicant(s)/Patent Under

Reexamination

HUNTER ET AL.

Examiner

John F. Belena, Ph.D.

Art Unit

3746

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,545,018	08-1996	Sundberg, Jack G.	418/30
	B	US-5,545,014	08-1996	Sundberg et al.	417/204
	C	US-5,141,418	08-1992	Ohtaki et al.	418/26
	D	US-5,052,896	10-1991	Fischer et al.	417/220
	E	US-4,710,106	12-1987	Iwata et al.	417/213
	F	US-4,468,173	08-1984	Dantlgraber, Jorg	417/220
	G	US-3,918,855	11-1975	Bornholdt, Siegfried	418/24
	H	US-4,850,269	07-1989	Hancock et al.	99/323.1
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 62294790 A	12-1987	Japan	TAKAGI et al.	F04C 15/04
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	W				
	X				

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